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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Complete If Known		
			Application Number	10/662,653-Conf. #9391	
			Filing Date	September 15, 2003	
			First Named Inventor	Michael P. Nowak	
			Art Unit	2863	
			Examiner Name	T. S. Lau	
Sheet	1	of	1	Attorney Docket Number	65858-0026/02-rASD-183

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
TL	AA	US-5,850,469-A	12-15-1998	Martin et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	BA	-				

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
TL	CA	PCT International Search Report (4 pages)	
TL	CB	Borgefors, Gunilla; "Hierarchical Chamfer Matching: A Parametric Edge Matching Algorithm"; IEEE Transactions On Pattern Analysis And Machine Intelligence; IEEE Inc., New York; Vol. 10, No. 6, November 1988; pgs. 849-865; XP002114858	
TL	CC	Cobzas, Dana, et al.; "Image-Based Localization With Depth-Enhanced Image Map"; PROC2003 INT.; IEEE Conf. Robotics and Automation; Vol. 2, September 14, 2003; pgs. 1570-1575; XP010667213	
TL	CD	Horn, Joachim, et al.; "Localization Of A Mobile Robot By Matching 3D-Laser-Range-Images And Predicted Sensor Images"; Intelligent Vehicles '94 Symposium, Paris, 24 October 1994; pgs. 345-350; XP010258393	
TL	CE	Zingaretti, P. et al.; "Image Segmentation For Appearance-Based Self-Localisation"; 11th International Conference On Image Analysis And Processing; September 26, 2001; pgs. 113-118; XP010561233	
TL	CF	Dudek, Gregory, et al.; "Vision-Based Robot Localization Without Explicit Object Models"; Proceedings of the 1996 IEEE International Conference on Robotics And Automation; Minneapolis, MN; April 22-28, 1996; pgs. 76-82; XP010162733	

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Examiner Signature		Date Considered	3-3-05
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